Application/Control No.	Applicant(s)/Patent under Reexamination	
10/706,987	TEI ET AL.	
Examiner	Art Unit	
Helen L. Pezzuto	1713	

SEARCHED					
Class	Subclass	Date	Examiner		
526	333				
	336	3/17/2006	HP		
Above	updated	9/8/2006	HP		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
			<u></u>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
STIC STN search	2/15/2006	НР	
West, Inventors search	3/17/2006	НР	
West, inventors search updated	9/8/2006	НР	